# Verification of Compliance

Product Name

: PCI Half-Size SBC

Model Number

: xxxxHSB-945Pxx-xxx-xxxxxxx

(Where x is 0-9 · A-Z · - or blank) for marketing purpose

Applicant

: AAEON Technology Inc.

Address

: 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan,

R.O.C.

Report Number

: F-U070-0909-273

Issue Date

September 30, 2009

Applicable Standards: FCC Part 15, Subpart B Class A ITE

ANSI C63.4:2003

Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE

One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.





NVLAP LAB CODE 200575-0

TAF 0905 FCC CAB Code TW1053 IC Code 4699A VCCI Accep. No. R-1527, C-1609, T-131, T-1441, G-10



Central Research Technology Co.

**EMC Test Laboratory** 11, Lane41, Fushuen St., Jungshan Chiu,

Taipei, Taiwan, 104, R.O.C. Tel: 886-2-25984568

Fax: 886-2-25984546

(Tsun-Yu Shih/ General Manager)

Date: September 30, 2009

# **FCC Test Report**

for

#### **PCI Half-Size SBC**

Model Number: xxxxHSB-945Pxx-xxx-xxxxxxx

(Where x is 0-9, A-Z, - or blank) for

marketing purpose

Report Number : F-U070-0909-273

Date of Receipt: September 24, 2009

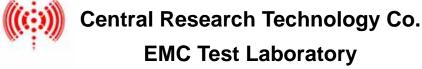
Date of Report : September 30, 2009

Prepared for

## **AAEON Technology Inc.**

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R.O.C.





11, Lane41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.



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# Verification of Compliance

: PCI Half-Size SBC **Equipment Under Test** 

Model No. : xxxxHSB-945Pxx-xxx-xxxxxxx

(Where x is 0-9, A-Z, - or blank) for marketing purpose

**Applicant** : AAEON Technology Inc.

**Address** : 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei,

Taiwan, R.O.C.

: FCC Part 15, Subpart B Class A ITE Applicable Standards

ANSI C63.4:2003

**Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE** 

Date of Testing : September 24~25, 2009

**Deviation** : N/A

Condition of Test Sample : Engineering Sample

We, Central Research Technology Co., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY

APPROVED BY

Ywen Huang/System Executive), DATE: Sept. 30, 2009

(Tsun-Yu Shih/General Manager)

TEL.: 886-2-25984542 FAX.: 886-2-25984546 Page: 2 / 41

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## 1. General Description

#### 1.1 General Description of EUT

Equipment Under Test : PCI Half-Size SBC

Model No. : xxxxHSB-945Pxx-xxx-xxxxxxx

(Where x is 0-9, A-Z, - or blank) for marketing

purpose

Power in : Supplied by the power supply of the host system.

Highest Operating Frequency : 1.6GHz

Manufacturer : AAEON Technology Inc.

Function Description :

The EUT is an engineering sample of the PCI Half-Size SBC. Please refer to the user's manual for the details.

The I/O ports of the EUT are listed below:

No.	I/O Port Type	Quantity
1	PS/2 port	1
2	USB port	5
3	D-Sub port	1
4	DVI port	1
5	RS232 port	4
6	Audio input port	1
7	Mic. port	1
8	Audio output port	1
9	LAN port	2

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All the devices listed below to equip a host system are supplied by the manufacturer to be tested in this report.

Components	Model
M/B	HSB-945P
CPU	Intel Atom N270 1.6GHz
Memory	DSL DDR2-667 512MB/ELPIDA E5108AGBG-6E-E
HDD	WD800BB , 80GB
PSU	FSP180-50PLA , 180Watts

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#### 1.2 Test Mode

There are two test modes are shown as below for preliminary test.

Test Mode	Mode	de Description	
Mode 1	Expose case for EUT	DVI+D-Sub 1280 x 1024@60Hz	
Mode 2	Enclosure case for EUT	DVI1 D-300 1200 X 102+@00112	

The Mode 2 was selected by its manufacturer to perform all tests. It was taken as the representative condition for the testing and its data are recorded in the present document.

# 1.3 Applied standards

According to the specifications of the manufacturers, the applied standard to evaluate the compliance of requirements is 47CFR Part 15, Subpart B and the measurement procedures specified in ANSI C63.4 are performed.

According to 47CFR Part 15 Section 15.33(b), the test frequency range of radiated emission measurements are listed below and the EUT herein shall be tested as:

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 1.705	30
	1.705 - 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 <sup>th</sup> harmonic of the highest
$\square$	Above 1000	frequency or 40GHz,
		whichever is lower

All the test items are as following:

Applied Standards	Test Items	Results
FCC Part 15, Subpart B	☑ Conducted Emission Measurement	<u>PASS</u>
Class A ITE	☑ Radiated Emission Measurement	<u>PASS</u>

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## 1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard through the following steps:

- a. Connect the host system and all the support units to the appropriate power source.
- b. Turn on the host system and all the accessories and support units.
- Install an EMC test software into host system and execute it under the Windows environment.
- d. The EUT reads/ writes message from/ to the USB Flash Disks continuously.
- e. The EUT plays the 1kHz sound signals to the earphone.
- f. The EUT sends "H" patterns to the monitor which fills the whole screen of it.
- g. The EUT sends messages to the modem.
- h. The EUT sends "H" patterns to the printer which prints them on paper.
- i. Another PC sends/ receives messages to/ from the EUT through a Hub by executing the command of "PING".
- j. Repeat and keep setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program
EUT	WIN EMC+EMC Test	
Monitor	+	V1.5
USB Flash Disk	1kHz	

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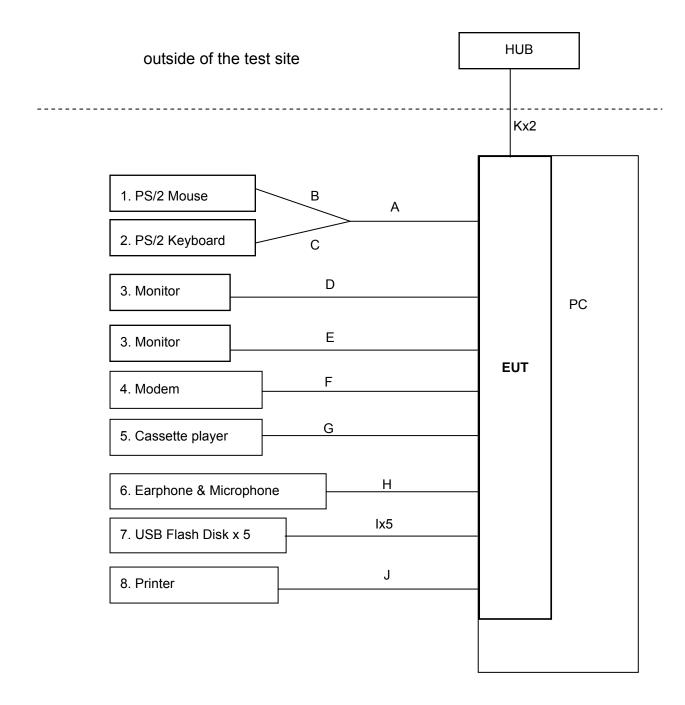
#### **The Support Units** 1.5

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PS/2 Mouse	PS/2 Mouse MO71KC / 515044951		DELL	N/A	<b>✓</b>
2	PS/2 Keyboard	SK-8110/ MY-05N456-71619- 53A-0546	DoC	DELL	N/A	✓
	Monitor	2408WFP / CN-0G293H-74261- 87C-0NLS-A00	DoC	DELL	1.8m	✓
3	Monitor	2408WFP / CN-0G293H-74261- 96M-068S	DoC	DELL	1.8m	✓
	Modem	DM-1414/ 0205002867	IFAXDM1414	ACEEX	1.9m	<b>√</b>
4		DM-1414/ 0505012779	IFAXDM1414	ACEEX	1.9m	<b>✓</b>
4		DM-1414/ 0505012774	IFAXDM1414	ACEEX	1.9m	<b>✓</b>
		DM-1414/ 0609026980	IFAXDM1414	ACEEX	1.9m	<b>✓</b>
5	Cassette player	RQ-L11/ 4-717523-100921-1	N/A	Panasonic	N/A	<b>✓</b>
6	Earphone & Microphone	MIC-4/ 2008-008	N/A	SCE	N/A	<b>✓</b>

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No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.
	USB Flash Disk	U172/ 100-017	D0C	PQI	N/A	<b>~</b>
		U172/ 100-028	D0C	PQI	N/A	<b>✓</b>
7		U172/ 100-036	D0C	PQI	N/A	<b>✓</b>
		U172/ 100-043	D0C	PQI	N/A	<b>~</b>
		U172/ 100-047	D0C	PQI	N/A	<b>~</b>
8	Printer	LQ-300+/ DCGY099001	N/A	EPSON	1.9m	<b>~</b>

# 1.6 Layout of the Setup



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# **Connecting Cables:**

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	PS/2 Cable	0.2m	<b>✓</b>				
В	PS/2 Mouse Cable	1.8m	✓			✓	
С	PS/2 Keyboard Cable	2.0m	✓			✓	
D	VGA Cable	1.7m	✓	✓		✓	2 cores
Е	DVI Cable	1.8m	✓	✓		✓	2 cores
F	Modem Cable	1.8m	✓	✓		✓	2 cores
G	Audio Cable	1.5m	✓			✓	
Н	Earphone & Microphone Cable	1.8m	<b>√</b>			✓	
I	USB Cable	1.8m	✓			✓	
J	Printer Cable	1.8m	✓			✓	
K	LAN Cable	>3m				✓	

(Note: The details Cable A is shown in the photographs in Attachment 1.)

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# 1.7 Test Capability

# **Test Facility**

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3 and ANSI C63.4.

Test Room Type of Test Room		Descriptions	
TR1	10m semi-anechoic chamber (23m $\times$ 14m $\times$ 9m)	Complying with the NSA requirements in documents CISPR 22 and ANSI C63.4.	
TR11	3m semi-anechoic chamber	for the radiated emission measurement.	
IKII	$(9m \times 6m \times 6m)$		
TR5	Shielding Room	For the conducted emission	
IKS	$(8m \times 5m \times 4m)$	measurement.	

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# **Test Laboratory Competence Information**

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
Accreditation	R.O.C. (Taiwan)	TAF	0905	ISO/IEC 17025
Certificate	R.O.C. (Taiwan)	BSMI	SL2-IN-E-0033, SL2-IS-E-0033, SL2-R1/R2-E-0033, SL2-A1-E-0033	ISO/IEC 17025
	USA	FCC	474046,TW1053	Test facility list & NSA Data
Site Filing Document	Canada	IC	4699A-1,-3	Test facility list & NSA Data
	Japan	VCCI	R-1527,C-1609,T-131,T-1441, G-10	Test facility list & NSA Data
Authorization	Germany	TUV	10021687-2007	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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#### 2. Conducted Emission Measurement

Test Result : PASS

#### 2.1 Limits for Emission Measurement

### ☑ Limits for conducted disturbances at the power mains

Fraguancy	Class A Equipment		Class B Equipment	
Frequency (MHz)	Quasi-peak	Average	Quasi-peak	Average
(1711 12)	(dBµV)	(dBµV)	(dBµV)	(dBµV)
0.15 to 0.5	79	66	66 – 56	56 – 46
0.5 to 5	73	60	56	46
5 to 30	73	60	60	50

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

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#### **Test Instruments** 2.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacturei	Serial No.	<b>Calibration Date</b>	Due Date	
Test Receiver	R&S	ESCS 30/	Jan. 13, 2009	Jan. 13, 2010	
lest Receiver	Κασ	836858/021	Jan. 13, 2009	Jan. 13, 2010	
LISN	R&S	ESH2-Z5/	Aug 14 2000	Aug. 14, 2010	
LISIN	Κασ	836613/001	Aug. 14, 2009	Aug. 14, 2010	
2 <sup>nd</sup> LISN	R&S	ENV4200/	lon 12 2000	In 10 0010	
2 LISIN	Ras	833209/010	Jan. 13, 2009	Jan. 13, 2010	
50Ω terminator	N/A	N/A/	Aug 26 2000	Aug. 26, 2010	
5012 terminator		001	Aug. 26, 2009		
RF Switch	N/A	RSU28/	Aug. 26, 2009	Feb. 26, 2010	
KF SWILCH	IN/A	338965/002			
RF Cable	N/A	N/A/	A 20, 2000	Fab 00 0040	
RF Cable	IN/A	C0052 ~ 56	Aug. 26, 2009	Feb. 26, 2010	
Test Software	Audix	e3/	NCR	NCD	
iesi soliwale	Audix	Ver. 5.2004-2-19k	NUR	NCR	
TR5	ETS	TR5/	NCR	NCD.	
shielded room	LINDGREN	15353-F	INCK	NCR	

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.

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# **Measurement Uncertainty**

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than  $U_{cispr}$  in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.1dB
	ENV 4200	3.8dB

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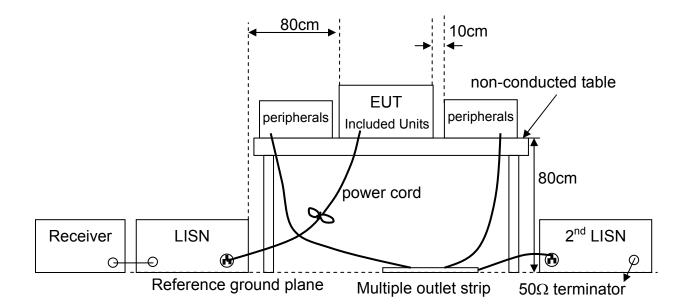
#### 2.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane.
- c. Connect the EUT's power source to the appropriate power mains through the LISN.
- d. All the other peripherals are connected to the 2<sup>nd</sup> LISN, if any.
- e. The LISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- Record the level for each frequency and compare with the required limit.

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# 2.4 Test Configurations



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#### **Photographs of the Test Configurations** 2.5





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#### 2.6 Test Results

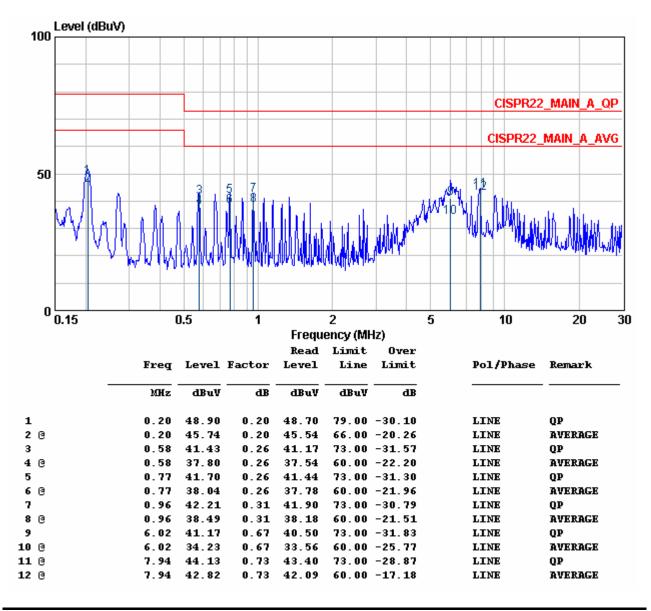
Test Mode : Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester**: Albert **Temperature**: 29°C

Humidity: 65%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Line



#### Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

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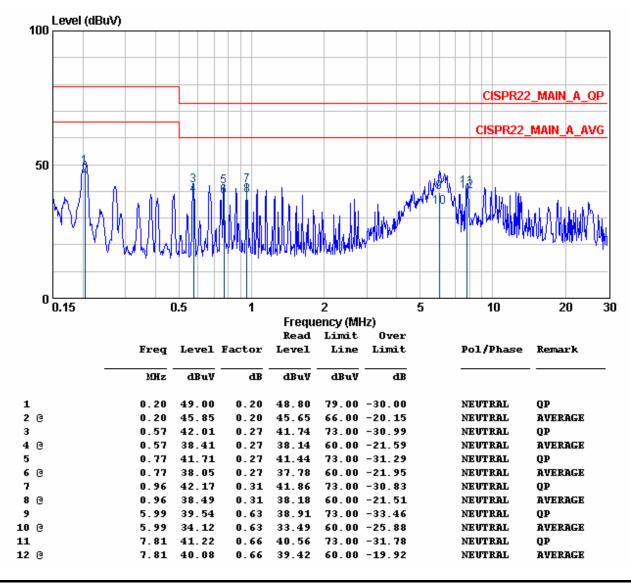
Test Mode : Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester**: Albert **Temperature**: 29°C

Humidity: 65%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase : Neutral



#### Note:

- Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

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#### 3. Radiated Emission Measurement

Test Result : PASS

#### 3.1 Limits for Emission Measurement

#### ☑ Limits for radiated disturbances below 1000MHz

Frequency	Class A Equipment (10m distance)	Class B Equipment (3m distance)
(MHz)	Quasi-peak	Quasi-peak
	(dBµV/m)	(dBµV/m)
30 to 88	39.1	40
88 to 216	43.5	43.5
216 to 960	46.4	46
960 to 1000	49.5	54

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

Note 3- According to 15.109(g), as an alternative to the radiated emission limits shown above, digital devices may be shown to comply with the standards (CISPR), Pub. 22 shown as below.

30 to 230	40	30
230 to 1000	47	37

# ☐ Limits for radiated disturbances in the frequency range 1000MHz ~ 2000MHz at a measuring distance of 10m

Frequency (GHz)	Class A Ed	Class A Equipment		quipment
	Peak	Average	Peak	Average
(0112)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 2	69.5	49.5	63.5	43.5

# ☑ Limits for radiated disturbances above 1000MHz at a measuring distance of 3m

Frequency	Class A Ed	Class A Equipment		quipment
(GHz)	Peak	Average	Peak	Average
(0112)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 40	80	60	74	54

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#### 3.2 Test Instruments

#### ☑ For Measurement at the distance of 10m

Test Site and	Manutacturer		Last	Calibration
Equipment		Serial No.	Calibration Date	Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Aug. 17, 2009	Aug. 17, 2010
Broadband Antenna	R&S	HL-562/ 360543/007	March 12, 2009	March 12, 2010
Broadband Antenna	R&S	HL-562/ 830547/010	Dec. 16, 2008	Dec. 16, 2009
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	Aug. 26, 2009	Feb. 26, 2010
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	Aug. 26, 2009	Feb. 26, 2010
Spectrum	R&S	FSP7/ 100384	Dec. 16, 2008	Dec. 16, 2009
Spectrum	R&S	FSP 7/ 100108	June 1, 2009	June 1, 2010
RF Cable	JYEBAO	0214/ C0049	July 22, 2009	Jan. 22, 2010
RF Cable	JYEBAO	0214/ C0050	July 22, 2009	Jan. 22, 2010
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	Nov. 22, 2008	Nov. 22, 2009

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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#### ☑ For Measurement at the distance of 3m

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESCI/ 100019	Nov. 25 2008	Nov. 25, 2009
Bi-Log Antenna	EMCO	3142C/ 52088	July 22, 2009	July 22, 2010
Horn Antenna	EMCO	3117/ 57416	March 3, 2009	March 3, 2010
	Mini Circuit	ZKL-2/ 004	Aug. 10, 2009	Feb. 10, 2010
Pre-Amplifier	MITEQ	AMF-4D-005180- 24-10P/ 1072961	Dec. 19, 2008	Dec. 19, 2009
	MITEQ	AFS6-02001800- 35-10P-6/ 866643	Dec. 19, 2008	Dec. 19, 2009
Spectrum Analyzer	Agilent	E4407B/ MY45106795	March 19, 2009	March 19, 2010
RF Cable	N/A	N/A/ C0080	Aug 10, 2009	Feb. 10, 2010
RF Cable	N/A	N/A/ C0081	April 24, 2009	Oct. 23, 2009
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR11 Semi - anechoic Chamber	ETS. LINDGREN	TR11/ 906-A	June 29, 2009	June 29, 2010

#### Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR : No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

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# **Measurement Uncertainty**

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than  $U_{cispr}$  in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequency Range		
(Measuring distance)	i olarization	30MHz ~200MHz	200MHz ~1000MHz	
TR1(10m)	Horizontal	3.5dB	3.4dB	
11(10111)	Vertical	3.6dB	3.2dB	
TR11(3m)	Horizontal	2.8dB	3.4dB	
Tivi (om)	Vertical	3.5dB	2.8dB	

Test Site	Polarization	Frequency Range
(Measuring distance)	1 Glarization	1GHz ~18GHz
TR11(3m)	Horizontal	2.5dB
(6)11)	Vertical	2.5dB

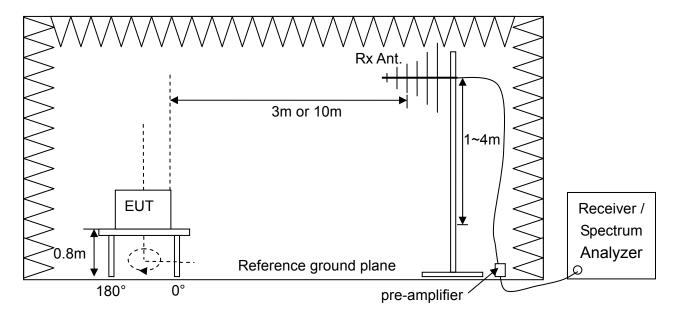
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#### 3.3 Test Procedures

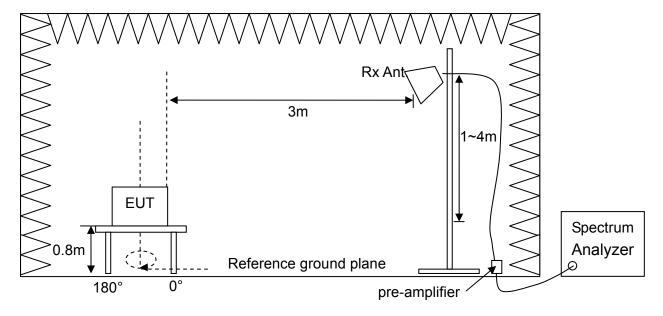
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane in the semi-anechoic chamber. If the EUT is floor-standing equipment, it was placed on a nonconducted support with a height of 12 millimeters above the reference ground plane in the semi-anechoic chamber.
- c. For the measurement of frequency below 1000MHz, the EUT was set 10m away from the interference receiving antenna for the limit of Class A equipment or CISPR 22. For Class B equipment and the measurement of frequency above 1000MHz, the EUT was set 3m away from the interference receiving antenna.
- d. Rapidly sweep the signal in the test frequency range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. For measurement of frequency above 1000MHz, the beamwidth of receiving horn antenna should keep covering EUT when the receiving horn antenna height varied.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f.
- For measurement of frequency below 1000MHz, set the receiver detector to be Quasi-Peak per CISPR 16-1 to find out the maximum level occurred.
- For measurement of frequency above 1000MHz, set the spectrum detector to be Peak or Average to find out the maximum level occurred, if any.
- k. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- I. Change the receiving antenna to another polarization to measure radiated emission by following step d. to k. again.
- m. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

# 3.4 Test Configurations

#### Radiated Emission Measurement below 2000MHz



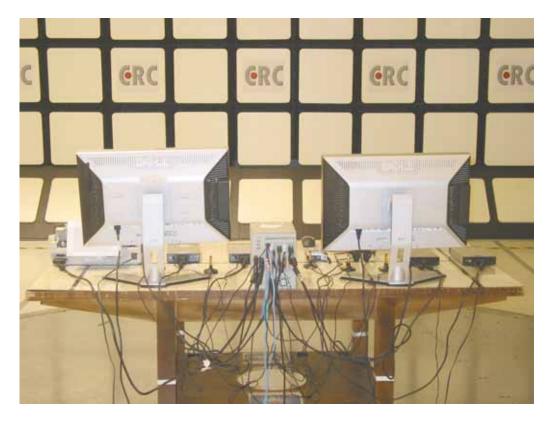
#### Radiated Emission Measurement above 1000MHz (if any)



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#### **Photographs of the Test Configurations** 3.5





#### 3.6 Test Results

#### Radiated Emission Measurement below 1000MHz

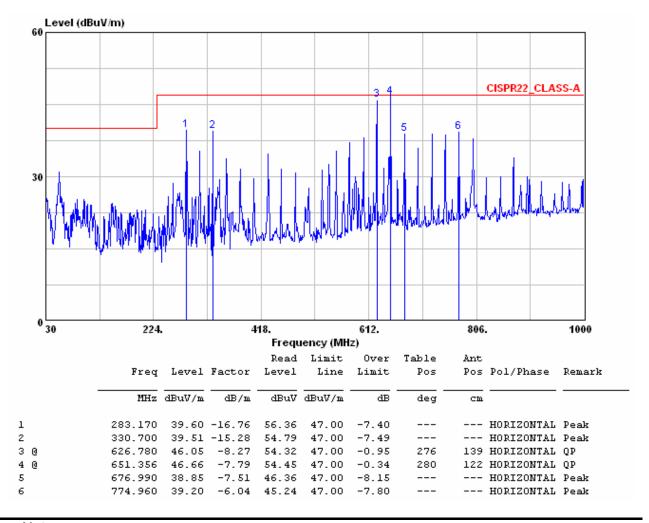
Test Mode : Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester** : Carl Yan **Temperature** : 27°C

Humidity: 67%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Horizontal



#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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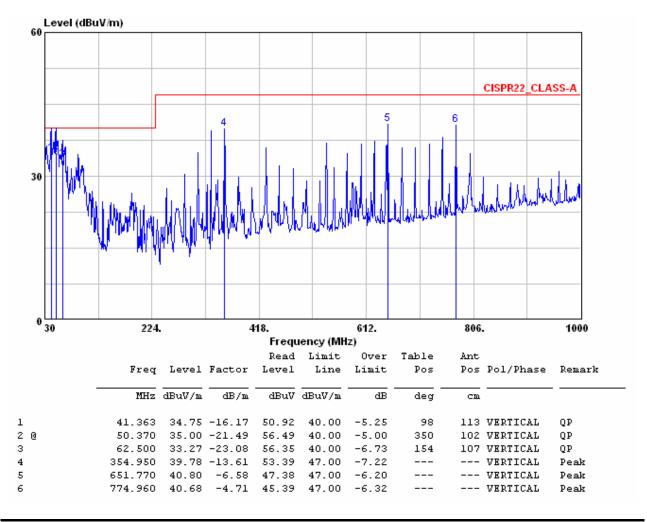
**Test Mode**: Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester**: Carl Yan **Temperature**: 27°C

Humidity: 67%RH Frequency Range: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Vertical



#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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#### Radiated Emission Measurement above 1000MHz

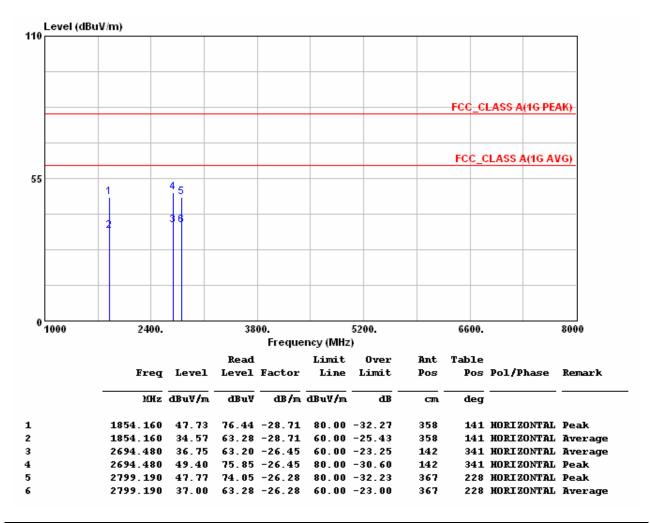
Test Mode : Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester**: Carl Yan **Temperature**: 26°C

Humidity: 68%RH Frequency Range: 1GHz~8GHz

IF Bandwidth: 1MHz Polarization: Horizontal



#### Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. PK. and AV. are abbreviation of peak and average respectively.

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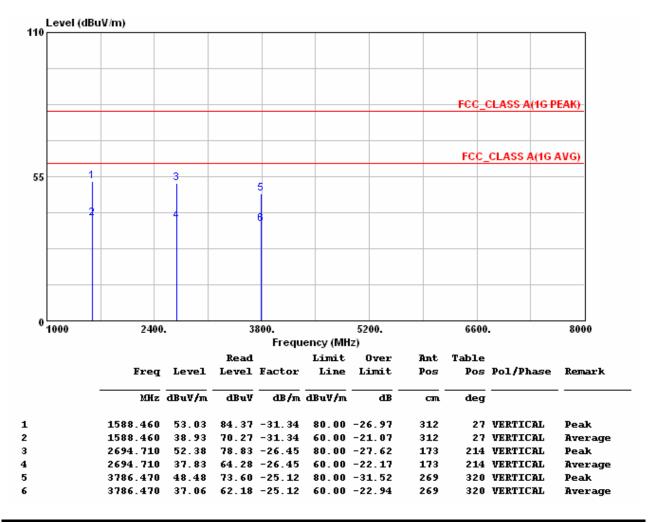
Test Mode : Mode 2

**Test Voltage**: 120V/60Hz to the host system

**Tester** : Carl Yan **Temperature** : 26°C

Humidity: 68%RH Frequency Range: 1GHz~8GHz

IF Bandwidth: 1MHz Polarization: Vertical



#### Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. PK. and AV. are abbreviation of peak and average respectively.

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# Attachment 1 Photographs of EUT

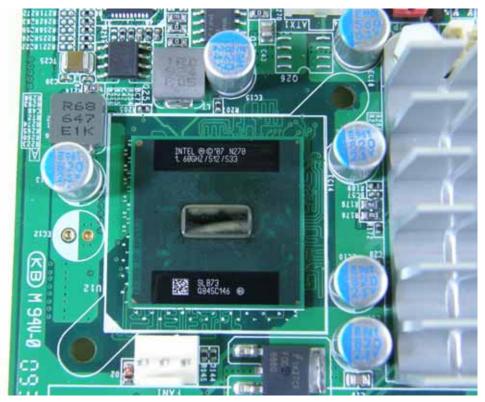
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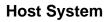




**Memory** 



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PS/2 Cable



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11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.
TEL.: 886-2-25984542
FAX.: 886-2-25984546

# Attachment 2 Modifications of EUT

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# Statement of the EUT Modifications

According to the rules of ANSI C63.4-2003 clause 10.1.13, the following equipment (EUT): PCI Half-Size SBC Product Model No. xxxxHSB-945Pxx-xxx-xxxxxxx (Where x is 0-9, A-Z, - or blank) for marketing purpose Manufacturer AAEON Technology Inc. 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Address Taiwan, R.O.C. ☐ should be without any modifications made ☐ should be with some modifications made to bring the EUT into compliance with the appropriate specifications (47CFR Part 15, Subpart B). If any, the details of the modifications including the complete descriptions, reasons and so on are described in next page of this report. , AAEON Technology Inc. hereby ensure that the product specified above will have all of the modifications incorporated in the product when manufactured and placed on the market. The following importer or manufacturer is responsible for this statement: Company Name Company Address: Telephone E-mail : Legal Signature of the responsible personal:

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Date

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Title / Name (full name)

The details of the modifications:

Item	Solution Component	Specifications	Manufacturer	Quantity	Reasons
1					
2					
3					
4					
5					
6					
7					
8					
9					
10					
11					
12					
13					
14					
15					

If needed, some modification items are shown in the photographs in the following.

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